

### General Description:

The GLZ24A8 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-220AB, which accords with the RoHS standard.

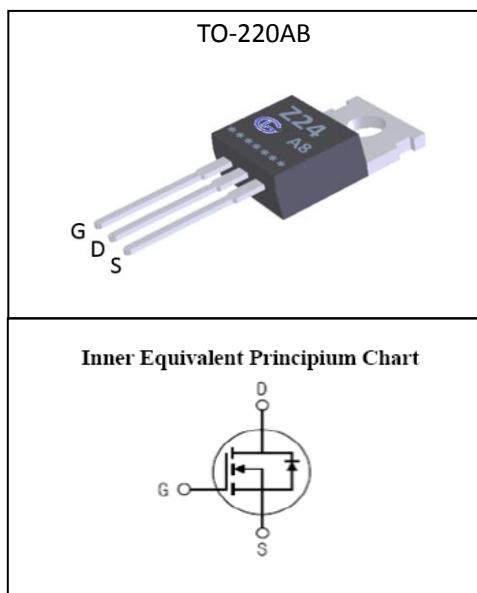
$V_{DSS}$	60	V
$I_D$	20	A
$P_D$	50	W
$R_{DS(ON)}$ type	23	$\text{m}\Omega$

### Features:

- Fast Switching
- Low Gate Charge and  $R_{DS(ON)}$
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

### Applications:

Power switching application  
Hard switched and high frequency circuits  
Uninterruptible power supply



**Absolute** ( $T_c = 25^\circ\text{C}$  unless otherwise specified):

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	60	V
$I_D$	Continuous Drain Current	20	A
	Continuous Drain Current $T_c = 100^\circ\text{C}$	14	A
$I_{DM}$	Pulsed Drain Current	80	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}^{a2}$	Single Pulse Avalanche Energy	80	$\text{mJ}$
$E_{AR}^{a1}$	Avalanche Energy ,Repetitive	4.5	$\text{mJ}$
$I_{AR}^{a1}$	Avalanche Current	11	A
$dv/dt^{a3}$	Peak Diode Recovery $dv/dt$	5.0	V/ns
$P_D$	Power Dissipation	50	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	175, -55 to 175	$^\circ\text{C}$
$T_L$	MaximumTemperature for Soldering	300	$^\circ\text{C}$



# GLZ24A8

## GL Silicon N-Channel Power MOSFET

**Electrical Characteristics** ( $T_c = 25^\circ C$  unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$V_{DSS}$	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	60	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A, Reference 25^\circ C$	--	0.1	--	$V/^\circ C$
$I_{DSS}$	Drain to Source Leakage Current	$V_{DS} = 60V, V_{GS} = 0V, T_a = 25^\circ C$	--	--	1	$\mu A$
		$V_{DS} = 48V, V_{GS} = 0V, T_a = 125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS} = +20V$	--	--	1	$\mu A$
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = -20V$	--	--	-1	$\mu A$

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=10A$	--	23	33	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	1.85	2.5	V
Pulse width $t_p \leqslant 380\mu s, \delta \leqslant 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$g_{fs}$	Forward Transconductance	$V_{DS}=5V, I_D = 5A$	11	--	--	S
$C_{iss}$	Input Capacitance		--	500	--	pF
$C_{oss}$	Output Capacitance	$V_{GS} = 0V, V_{DS} = 30V, f = 1.0MHz$	--	60	--	
$C_{rss}$	Reverse Transfer Capacitance		--	25	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 10A, V_{DD} = 30V, V_{GS} = 10V, R_G = 3.0\Omega$	--	5	--	ns
$t_r$	Rise Time		--	2.6	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	16	--	
$t_f$	Fall Time		--	2.3	--	
$Q_g$	Total Gate Charge	$I_D = 10A, V_{DD} = 30V, V_{GS} = 10V$	--	23	--	nC
$Q_{gs}$	Gate to Source Charge		--	4.5	--	
$Q_{gd}$	Gate to Drain ("Miller") Charge		--	6	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I <sub>S</sub>	Continuous Source Current (Body Diode)		--	--	20	A
I <sub>SM</sub>	Maximum Pulsed Current (Body Diode)		--	--	80	A
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =20A, V <sub>GS</sub> =0V	--	--	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =20A, T <sub>j</sub> = 25 °C dI <sub>F</sub> /dt=100A/us, V <sub>GS</sub> =0V	--	30	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	49	--	nC
Pulse width t <sub>p</sub> ≤380μs, δ ≤2%						

Symbol	Parameter	Typ.	Units
R <sub>θ JC</sub>	Junction-to-Case	2.5	°C/W
R <sub>θ JA</sub>	Junction-to-Ambient	62	°C/W

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

<sup>a2</sup>: EAS condition : T<sub>j</sub>=25 ,V<sub>DD</sub>= °C 30V,V<sub>G</sub>=10V,L=0.5mH,R<sub>g</sub>=25Ω

<sup>a3</sup>: I<sub>SD</sub> =20A,di/dt ≤100A/us,V<sub>DD</sub>≤BV<sub>DS</sub>, Start T<sub>j</sub>=25 °C

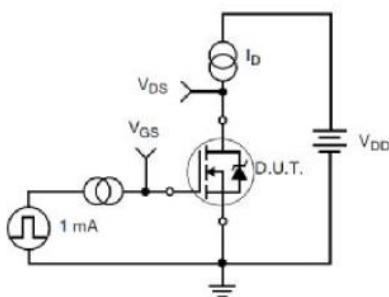
**Test Circuit and Waveform**


Figure 17. Gate Charge Test Circuit

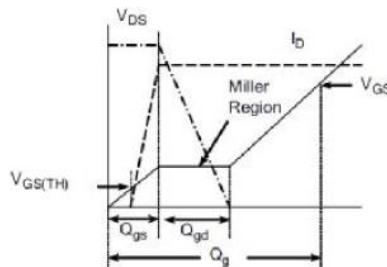


Figure 18. Gate Charge Waveform

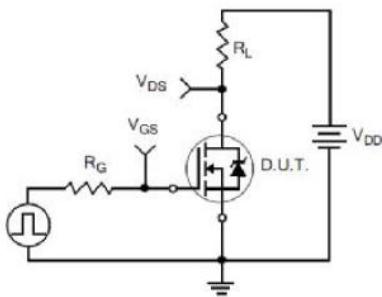


Figure 19. Resistive Switching Test Circuit

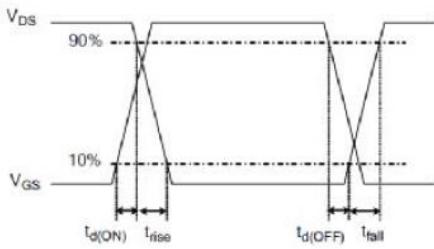
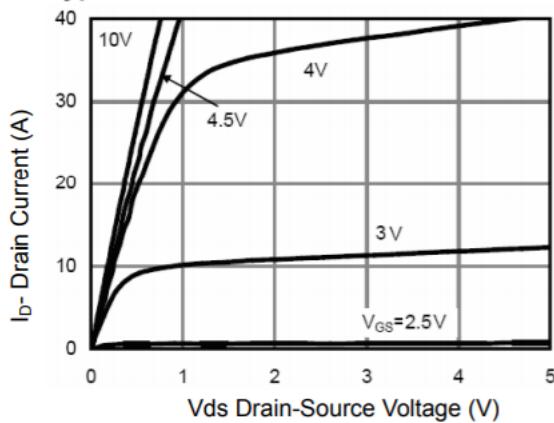
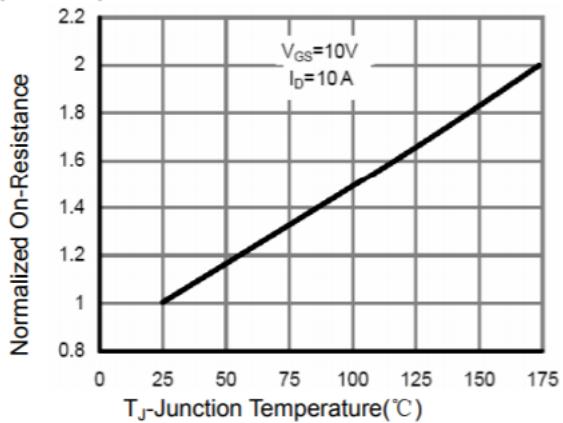
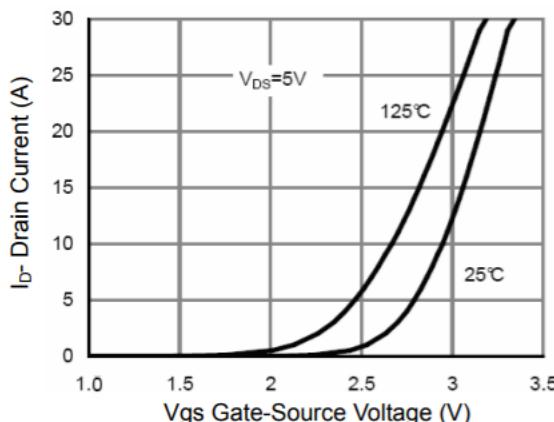
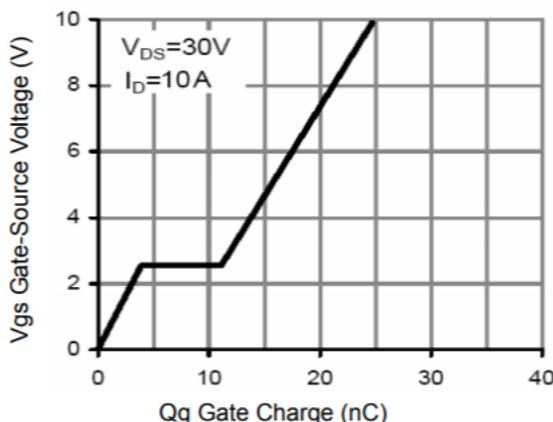
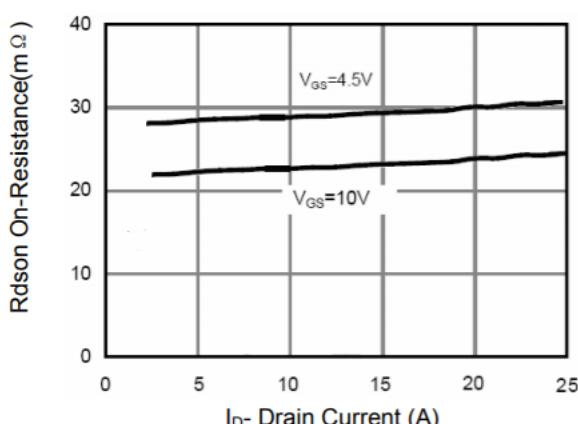
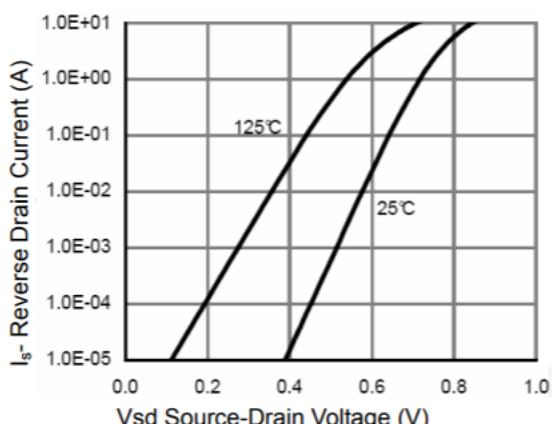
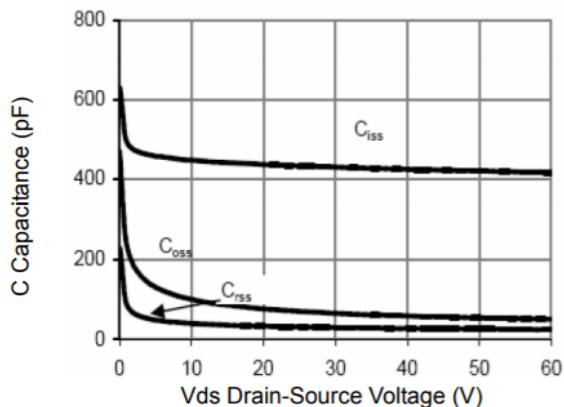
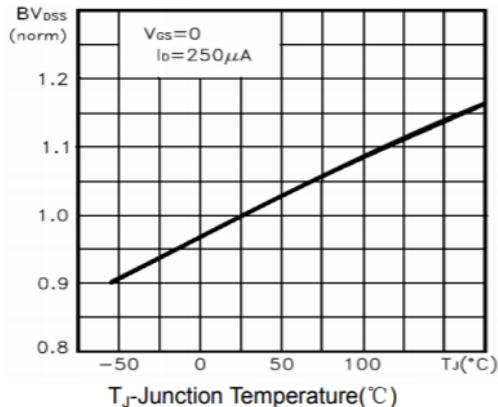


Figure 20. Resistive Switching Waveforms

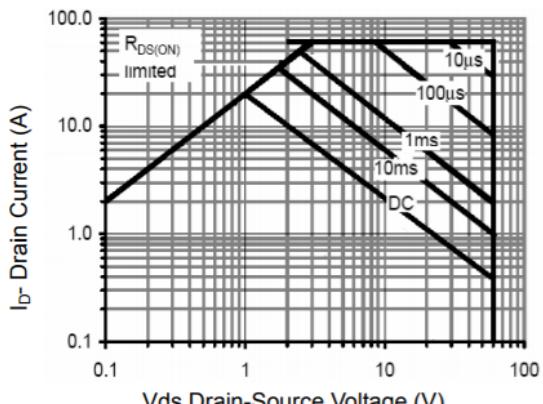
**Typical Electrical and Thermal Characteristics (Curves)**

**Figure 1 Output Characteristics**

**Figure 4 Rdson-Junction Temperature**

**Figure 2 Transfer Characteristics**

**Figure 5 Gate Charge**

**Figure 3 Rdson-Drain Current**

**Figure 6 Source-Drain Diode Forward**



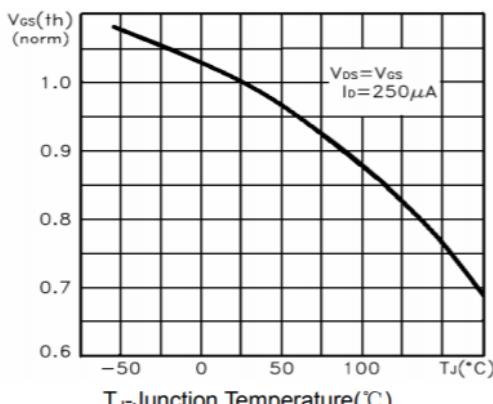
**Figure 7 Capacitance vs Vds**



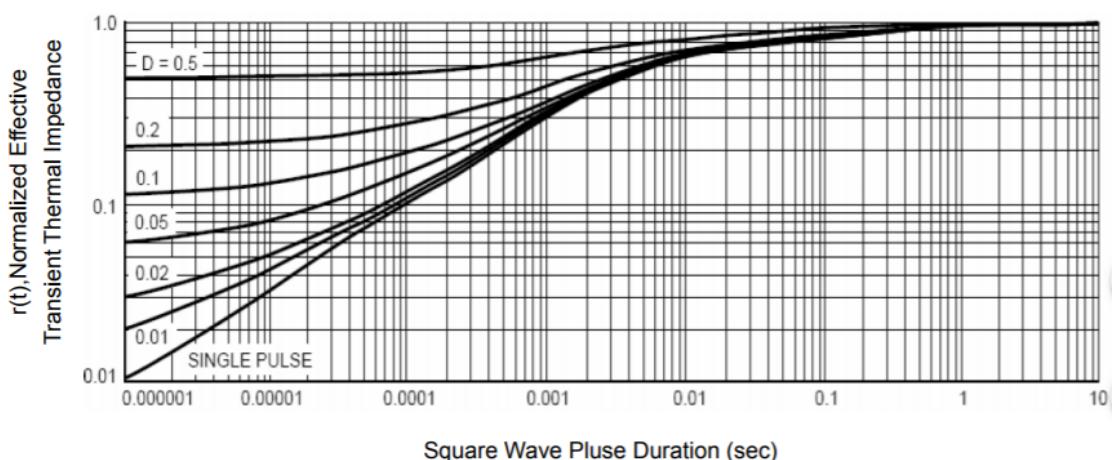
**Figure 9 BV<sub>DSS</sub> vs Junction Temperature**



**Figure 8 Safe Operation Area**



**Figure 10 V<sub>Gs(th)</sub> vs Junction Temperature**



**Figure 11 Normalized Maximum Transient Thermal Impedance**

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